

BUK7Y28-75B

N-channel TrenchMOS standard level FET

Rev. 03 — 18 February 2010

Objective data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using NXP High-Performance Automotive (HPA) TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Q101 compliant
- Suitable for standard level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- 12 V, 24 V and 42 V loads
- Automotive systems
- DC-to-DC converters
- Engine management
- General purpose power switching
- Solenoid drivers
- Transmission control

1.4 Quick reference data

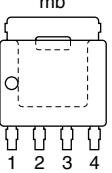
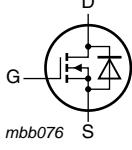
Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25^\circ\text{C}; T_j \leq 175^\circ\text{C}$	-	-	75	V
I_D	drain current	$V_{GS} = 10\text{ V}; T_{mb} = 25^\circ\text{C}$; see Figure 1 and 3	-	-	35.5	A
P_{tot}	total power dissipation	$T_{mb} = 25^\circ\text{C}$; see Figure 2	-	-	85	W
Dynamic characteristics						
Q_{GD}	gate-drain charge	$I_D = 15\text{ A}; V_{DS} = 60\text{ V}; V_{GS} = 10\text{ V}$; see Figure 15	-	7.4	-	nC
Static characteristics						
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10\text{ V}; I_D = 15\text{ A}; T_j = 25^\circ\text{C}$; see Figure 12 and 13	-	23	28	mΩ
Avalanche ruggedness						
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$I_D = 35.5\text{ A}; V_{sup} \leq 75\text{ V}; R_{GS} = 50\text{ }\Omega; V_{GS} = 10\text{ V}; T_{j(init)} = 25^\circ\text{C}$; unclamped	-	-	75	mJ



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source		
3	S	source		
4	G	gate		
mb	D	mounting base; connected to drain		
SOT669 (LFPAK)				

3. Ordering information

Table 3. Ordering information

Type number	Package	Name	Description	Version
BUK7Y28-75B	LFPAK		plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25^\circ\text{C}; T_j \leq 175^\circ\text{C}$	-	75	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20\text{ k}\Omega$	-	75	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$T_{mb} = 25^\circ\text{C}; V_{GS} = 10\text{ V}$; see Figure 1 and 3	-	35.5	A
		$T_{mb} = 100^\circ\text{C}; V_{GS} = 10\text{ V}$; see Figure 1	-	25.1	A
I_{DM}	peak drain current	$T_{mb} = 25^\circ\text{C}; t_p \leq 10\text{ }\mu\text{s}$; pulsed; see Figure 3	-	142	A
P_{tot}	total power dissipation	$T_{mb} = 25^\circ\text{C}$; see Figure 2	-	85	W
T_{stg}	storage temperature		-55	175	°C
T_j	junction temperature		-55	175	°C
Source-drain diode					
I_S	source current	$T_{mb} = 25^\circ\text{C}$	-	35.5	A
I_{SM}	peak source current	$t_p \leq 10\text{ }\mu\text{s}$; pulsed; $T_{mb} = 25^\circ\text{C}$	-	142	A
Avalanche ruggedness					
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$I_D = 35.5\text{ A}; V_{sup} \leq 75\text{ V}; R_{GS} = 50\text{ }\Omega$; $V_{GS} = 10\text{ V}; T_{j(init)} = 25^\circ\text{C}$; unclamped	-	75	mJ
$E_{DS(AL)R}$	repetitive drain-source avalanche energy	see Figure 4	[1][2][3]	-	J

[1] Single-pulse avalanche rating limited by maximum junction temperature of 175°C .

[2] Repetitive avalanche rating limited by an average junction temperature of 170°C .

[3] Refer to application note AN10273 for further information.

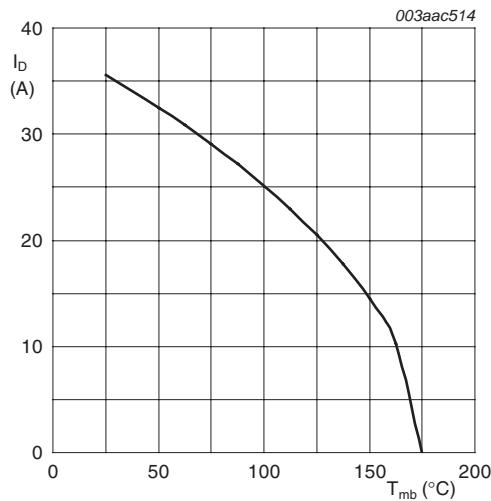
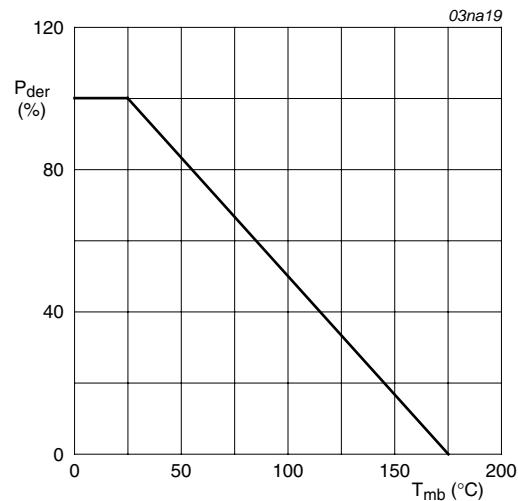
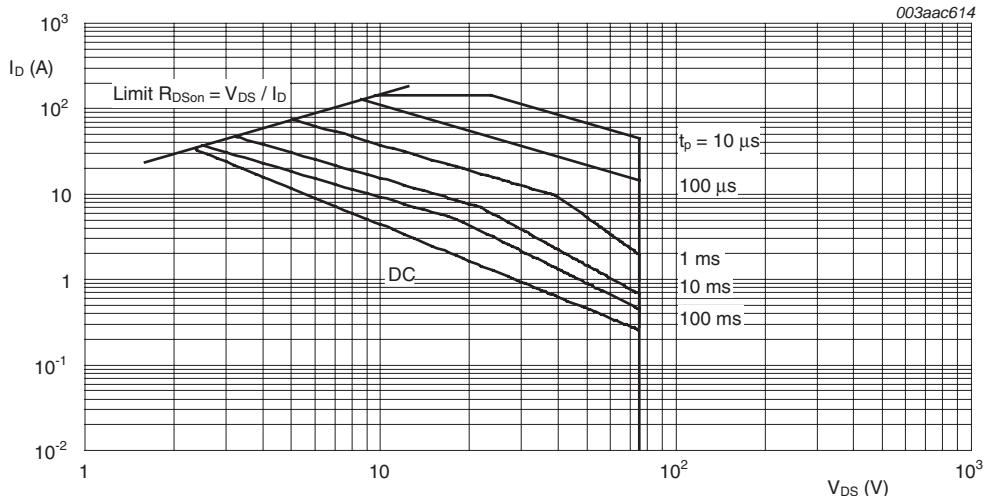


Fig 1. Continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot}(25^\circ C)} \times 100 \%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



$T_{mb} = 25^\circ C; I_{DM}$ is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

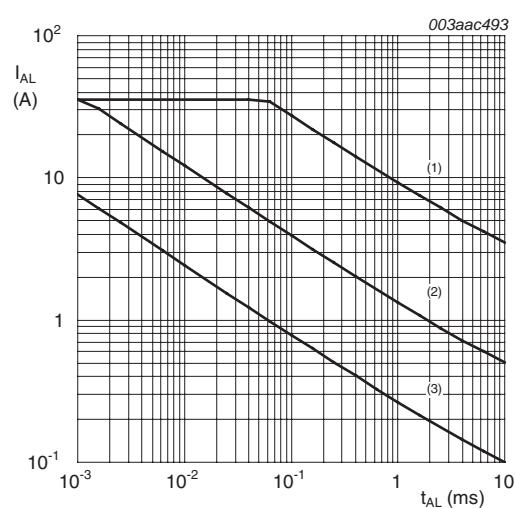


Fig 4. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j\text{-mb})}$	thermal resistance from junction to mounting base	see Figure 5	-	-	1.76	K/W

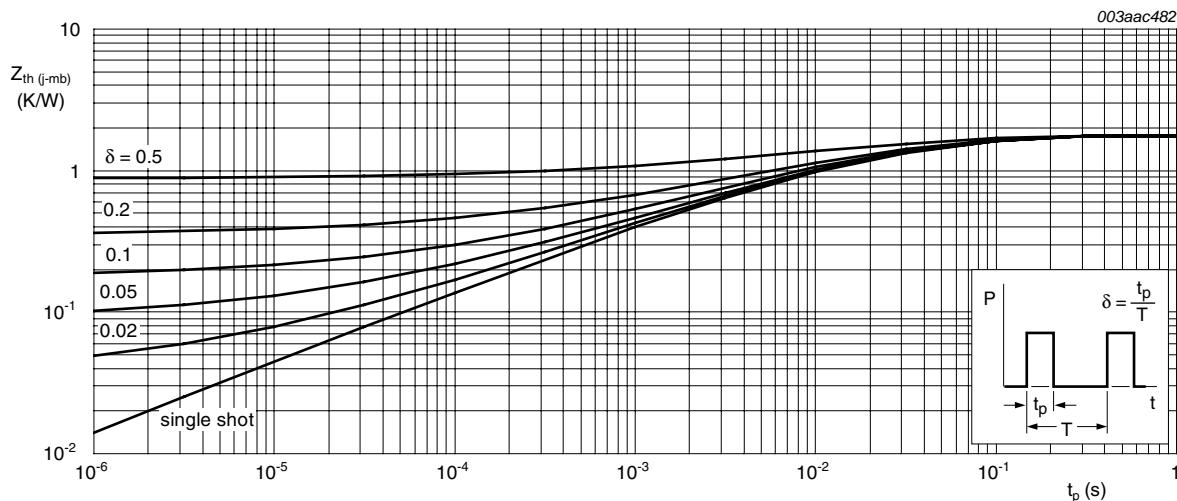
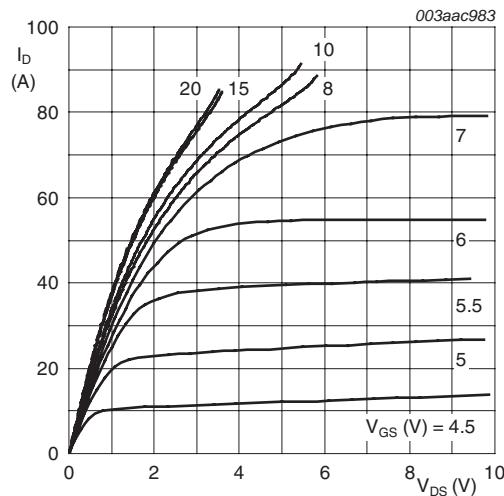
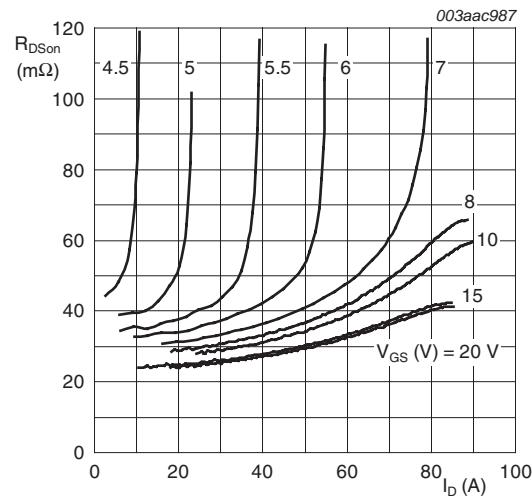
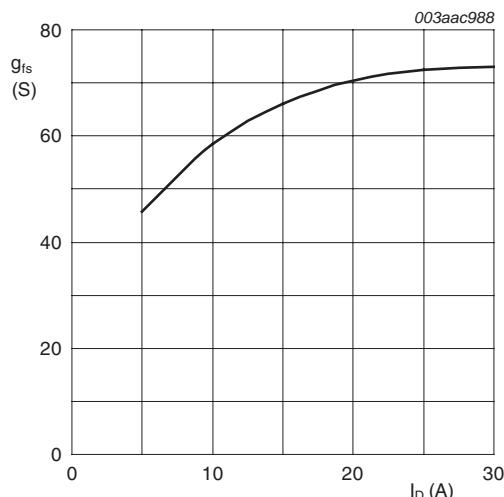
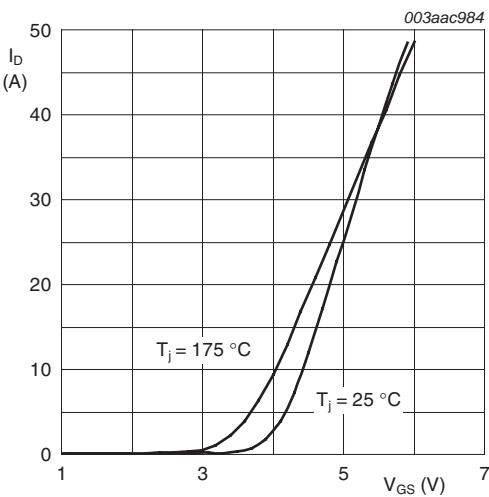


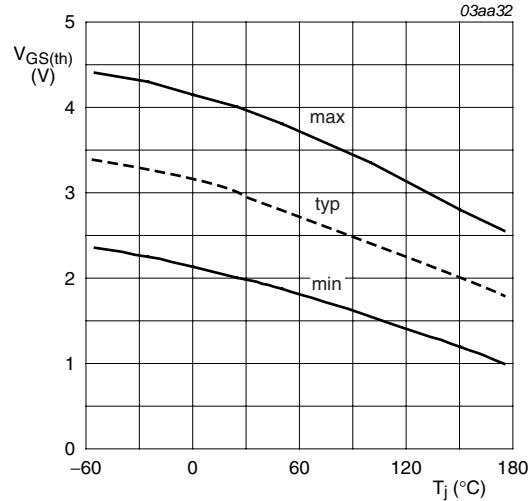
Fig 5. Transient thermal impedance from junction to mounting base as a function of pulse duration.

6. Characteristics

Table 6. Characteristics

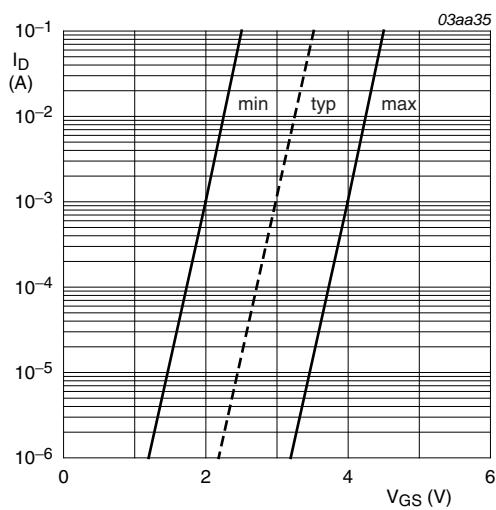
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25^\circ C$	75	-	-	V
		$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55^\circ C$	68	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 mA; V_{DS} = V_{GS}; T_j = 25^\circ C$; see Figure 10 and 11	2	3	4	V
		$I_D = 1 mA; V_{DS} = V_{GS}; T_j = -55^\circ C$; see Figure 10	-	-	4.4	V
		$I_D = 1 mA; V_{DS} = V_{GS}; T_j = 175^\circ C$; see Figure 10	1	-	-	V
I_{DSS}	drain leakage current	$V_{DS} = 75 V; V_{GS} = 0 V; T_j = 25^\circ C$	-	0.02	1	μA
		$V_{DS} = 75 V; V_{GS} = 0 V; T_j = 175^\circ C$	-	-	500	μA
I_{GSS}	gate leakage current	$V_{DS} = 0 V; V_{GS} = 20 V; T_j = 25^\circ C$	-	2	100	nA
		$V_{DS} = 0 V; V_{GS} = -20 V; T_j = 25^\circ C$	-	2	100	nA
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10 V; I_D = 15 A; T_j = 175^\circ C$; see Figure 12	-	-	67.2	$m\Omega$
		$V_{GS} = 10 V; I_D = 15 A; T_j = 25^\circ C$; see Figure 12 and 13	-	23	28	$m\Omega$
Dynamic characteristics						
$Q_{G(tot)}$	total gate charge	$I_D = 15 A; V_{DS} = 60 V; V_{GS} = 10 V$; see Figure 15	-	21.2	-	nC
Q_{GS}	gate-source charge		-	5	-	nC
Q_{GD}	gate-drain charge		-	7.4	-	nC
C_{iss}	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz; T_j = 25^\circ C$	-	1063	1417	pF
C_{oss}	output capacitance	see Figure 16	-	186	223	pF
C_{rss}	reverse transfer capacitance		-	74	101	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = 30 V; R_L = 2 \Omega; V_{GS} = 10 V; R_{G(ext)} = 10 \Omega$	-	7	-	ns
t_r	rise time		-	12.6	-	ns
$t_{d(off)}$	turn-off delay time		-	29.8	-	ns
t_f	fall time		-	7.1	-	ns
Source-drain diode						
V_{SD}	source-drain voltage	$I_S = 15 A; V_{GS} = 25 V; T_j = 25^\circ C$; see Figure 14	-	0.85	1.2	V
t_{rr}	reverse recovery time	$I_S = 20 A; dI_S/dt = -100 A/\mu s; V_{GS} = 0 V; V_{DS} = 30 V$	-	50	-	ns
Q_r	recovered charge		-	115	-	nC

 $T_j = 25^\circ C$ **Fig 6.** Output characteristics: drain current as a function of drain-source voltage; typical values. $T_j = 25^\circ C$ **Fig 7.** Drain-source on-state resistance as a function of drain current; typical values. $T_j = 25^\circ C; V_{DS} = 25 V$ **Fig 8.** Forward transconductance as a function of drain current; typical values. $V_{DS} = 25 V$ **Fig 9.** Transfer characteristics: drain current as a function of gate-source voltage; typical values.



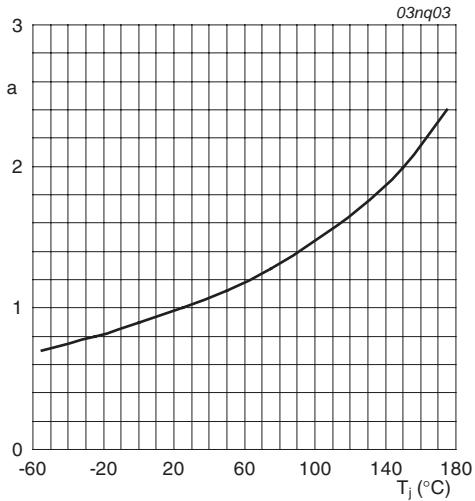
$I_D = 1\text{mA}; V_{DS} = V_{GS}$

Fig 10. Gate-source threshold voltage as a function of junction temperature



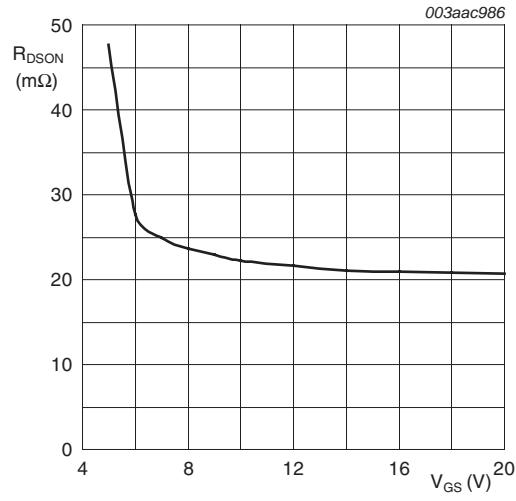
$T_j = 25^\circ\text{C}; V_{DS} = 5\text{V}$

Fig 11. Sub-threshold drain current as a function of gate-source voltage



$$a = \frac{R_{DSon}}{R_{DSon}(25^\circ\text{C})}$$

Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature



$T_j = 25^\circ\text{C}; I_D = 15\text{A}$

Fig 13. Drain-source on-state resistance as a function of gate-source voltage; typical values.

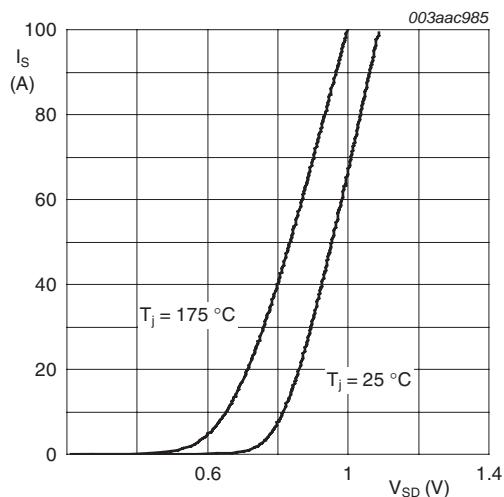


Fig 14. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.

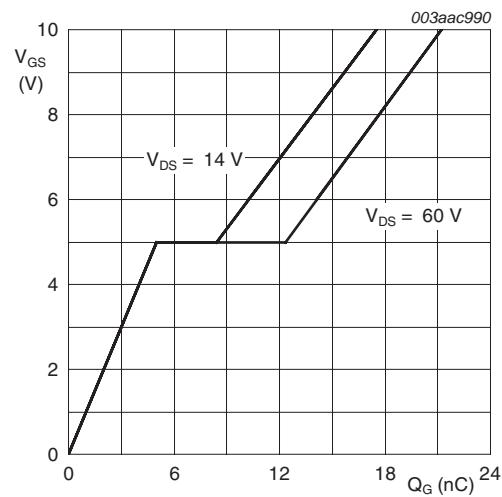
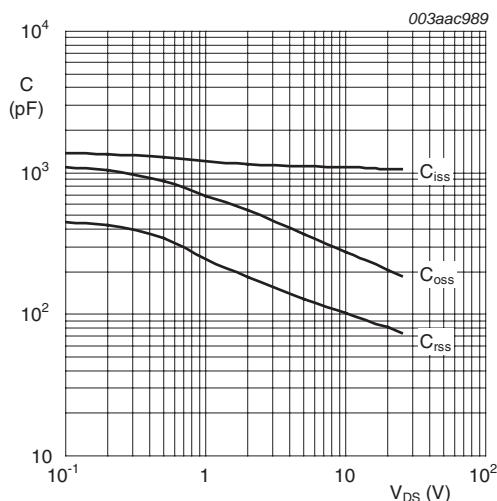


Fig 15. Gate-source voltage as a function of gate charge; typical values.



$V_{GS} = 0\text{ V}; f = 1\text{ MHz}$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.

7. Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669

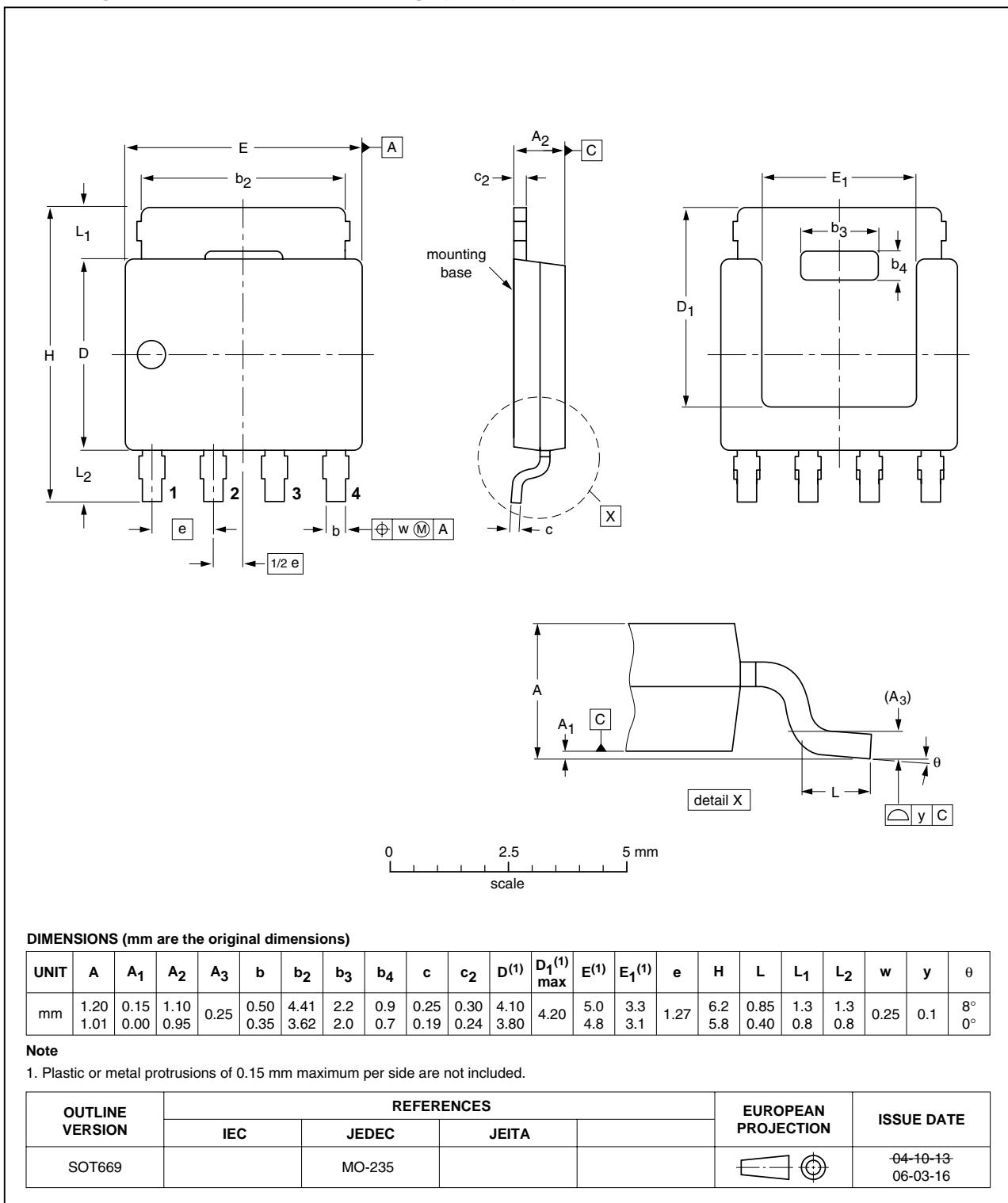


Fig 17. Package outline SOT669 (LFPAK)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7Y28-75B_3	20100218	Objective data sheet	-	BUK7Y28-75B_2
Modifications:		• Various changes to content.		
BUK7Y28-75B_2	20090803	Objective data sheet	-	BUK7Y28-75B_1
BUK7Y28-75B_1	20081216	Objective data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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